11/21/03

Form PTO-1449 (Rev.7-80)	U.S. Department of Commerce Patent & Trademark Office	ATTY.DOCKET NO. 9-14774-1US-1-1	SERIAL NO. 10/717460 Not yet assigned.
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT DAVID F. SKOLL et al.	
		FILING DATE: Concurrently herewith. 11-21-03	GROUP 2825

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
PD	AA	4,623,255	18 Nov/86	Suszko	356	389	13 Oct/83
PD	AB	5,086,477	4 Feb/92	Yu et al.	382	8	7 Aug/90
	AC	5,191,213	2 Mar/93	Ahmed et al.	250	310	5 July/91
	AD	5,561,293	1 Oct/96	Peng et al.	250	307	20 Apr/95
PD	AE	5,694,481	2 Dec/97	Lam et al.	382	145	12 Apr/95
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document number	Date	Country	Class	Subclass	Translation	
PD	AL	2,216,589	26 Sep/97	Canada	G06T	7/00		
PD	AM	2,216,900	26 Sep/97	Canada	G06T	7/60		
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

PD	AR	Article: "Chip Scanner System High Resolution SEM Image Capture and conversion from image to GDS-11 layout, George Lanzarotta, Raith USA, Inc., November 1999
PD	AS	Article" "Computer-Aided Reconstruction of IC Layout from Image-Based Representation" C.C. Jong et al., Sept. 1993, Proceedings of the 5th International Symposium on IC Technology, Systems ADN Applications, Nanyang Technological University, Singapore.
PD	AS	Article: "Integrated Circuit Chip Layer Analysis", Tan Ooi Kiang et al., Sept. 1993, Proceedings of the 5th International Symposium on IC Technology, System and Applications, Nanyang Technological University, Singapore.

Examiner PAUL DINH	Date considered 4/25/05

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.